THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re Application of:

Yoon, et al.

Serial No.: 10/074,898

Unknown Confirmation No.:

Filed:

February 11, 2002

For:

Deposition of Tungsten

Films

Assistant Commissioner for Patents Washington, D.C. 20231

Dear Sir:

Group Art Unit: Unknown

Examiner:

Unknown

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CERTIFICATE OF MAILING

37 CFR 1.8

I hereby certify that this correspondence is being deposited on June ______, 2002 with the United States Postal Service as First Class Mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231.

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Signature

INFORMATION DISCLOSURE STATEMENT

The Applicants, and the Attorney who signs below on the basis of the information supplied by the inventor and the information in his file, submit herewith patents, publications, or other information of which they are aware, which may be material to the examination of this application and in respect of which there may be a duty to disclose in accordance with 37 CFR § 1.56.

While the information submitted in this Information Disclosure Statement may be material pursuant to 37 CFR § 1.56, it is not intended to constitute an admission that any patent, publication, or other information referred to therein is prior art for this invention unless specifically designated as such.

In accordance with 37 CFR § 1.97, this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possibly material information as defined under 37 CFR § 1.56(a) exists.

The patents and/or publications submitted herewith are set forth on the attached Form PTO-1449.

If the sum of \$180.00 is due under 37 CFR § 1.17(p) pursuant to § 1.97, the Commissioner is hereby authorized to charge this fee, and any other fee necessary to make this submission timely, to the Deposit Account No. 20-0782/APPM/6473/BTP.

Respectfully submitted,

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Registration No. 34,102

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J.S. Depart	ment of	Commerce, Patent	and Trademar	k Office	Docket No.		Serial No.
PTO Form	1449 m	odified)			APPM/6473	3	10/074,898
		IST OF PATENTS	AND PUBLIC	ATIONS	Applicant		Confirmation No.:
ITED BY A	APPLIC	ANT	0	IPE of	Yoon, et al.		Unknown
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Examiner nitial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A1	4,058,430	11/15/77	Suntola et al.	156	611	11/25/75
	A2	4,389,973	6/28/83	Suntola et al.	118	725	12/11/81
	A3	4,413,022	11/1/83	Suntola et al.	427	255.2	6/21/79
	A4	4,486,487	12/4/84	Skarp	428	216	4/25/83
	A5	4,767,494	8/30/88	Kobayashi et al	. 156	606	9/19/86
	A6	4,806,321	2/21/89	Nishizawa et al	. 422	245	7/21/85
	A7	4,813,846	3/21/89	Helms	414	744.1	4/29/87
	A8	4,829,022	5/9/89	Kobayashi et al	. 437	107	12/9/86
	A9	4,834,831	5/30/89	Nishizawa et al	. 156	611	9/4/87
	A10	4,838,983	6/13/89	Schumaker et al.	156	613	3/18/88
	3 11	4,838,993	6/13/89	Aoki et al.	156	643	12/3/87
		4,840,921	6/20/89	Matsumoto	437	89	6/30/88
0.28	8212 A23 A24	4,845,049	7/4/89	Sunakawa	437	81	3/28/88
	A44	4,859,625	8/22/89	Nishizawa et al	. 437	81	11/20/87
RECEIVE	A15	4,859,627	8/22/89	Sunakawa	437	81	7/1/88
R	A16	4,861,417	8/29/89	Mochizuki et al	. 156	610	3/24/88
	A1元	4,876,218	10/24/89	Pessa et al.	437	107	9/26/88
	A18	4,917,556	4/17/90	Stark et al.	414	217	5/26/89
	A19	4,927,670	5/22/90	Erbil	427	255.3	6/22/88
	A20	4,931,132	6/5/90	Aspnes et al.	156	601	10/7/88
	A21	4,951,601	8/28/90	Maydan, et al.	118	719	6/23/89
	A22	4,960,720	10/2/90	Shimbo	437	105	8/24/87
	A23	4,975,252	12/4/90	Nishizawa et a	I. 422	245	5/26/89
	A24	4,993,357	2/19/91	Scholz	118	715	12/21/89
	A25	5,000,113	3/19/91	Wang et al.	118	723	12/19/86
	A26	5,013,683	5/7/91	Petroff et al.	437	110	1/23/89
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.



U.S. Depar	tment o	f Commerce, Pate	ent and Trader	mark Office	Docket No.		Serial No.
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A27	5,028,565	7/2/91	Chang, et al.	437	192	8/25/89
	A28	5,082,798	1/21/92	Arimoto	437	108	9/27/90
	A29	5,085,885	2/4/92	Foley et al.	477	38	9/10/90
	A30	5,091,320	2/25/92	Aspnes et al.	437	8	6/15/90
	A31	5,130,269	7/14/92	Kitahara et al.	437	111	4/25/89
	A32	5,166,092	11/24/92	Mochizuki et a	1. 437	105	10/30/90
	A33	5,173,474	12/22/92	Connell, et al.	505	1	3/11/91
	A34	5,186,718	2/16/93	Tepman et al.	29	25.01	4/15/91
	A35	5,205,077	4/27/93	Wittstock	51	165 R	8/28/91
	A36	5,225,366	7/6/93	Yoder	437	108	6/22/90
	A37	5,234,561	8/10/93	Randhawa et a	al. 204	192.38	8/25/88
	A38	5,246,536	9/21/93	Nishizawa et a	ıl. 156	610	3/10/89
-	A39	5,250,148	10/5/93	Nishizawa et a	ıl. 156	611	11/12/91
-	A40	5,254,207	10/19/93	Nishizawa et a	ıl. 156	601	11/30/92
	A41	5,256,244	10/26/93	Ackerman	156	613	2/10/92
	A42	5,259,881	11/9/93	Edwards, et al	. 118	719	5/17/91
	A43	5,270,247	12/14/93	Sakuma et al.	437	133	7/8/92
	A44	5,278,435	1/11/94	Van Hove et a	l. 257	184	6/8/92
	A45	5,281,274	1/25/94	Yoder	118	697	2/4/93
	A46	5,286,296	2/15/94	Sato et al.	118	719	1/9/92
	A47	5,290,748	3/1/94	Knuuttila et al.	502	228	7/16/92
	A48	5,294,286	3/15/94	Nishizawa et a	al. 156	610	1/12/93
	A49	5,296,403	3/22/94	Nishizawa et a	al. 437	133	10/23/92
	A50	5,300,186	4/5/94	Kitahara et al.	156	613	4/7/92
	A51	5,311,055	5/10/94	Goodman et a	l. 257	593	11/22/91
	A52	5,316,615	5/31/94	Copel	117	95	3/9/93

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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
	A53	5,316,793	5/31/94	Wallace et al.	427	248.1	7/27/92
	A54	5,330,610	7/19/94	Eres et al.	117	86	5/28/93
	A55	5,336,324	8/9/94	Stall et al.	118	719	12/4/91
	A56	5,338,389	8/16/94	Nishizawa et al.	117	89	4/21/93
	A57	5,348,911	9/20/94	Jurgensen et al.	117	91	4/26/93
	A58	5,374,570	12/20/94	Nasu et al.	437	40	8/19/93
	A59	5,395,791	3/7/95	Cheng et al.	437	105	10/20/93
	A60	5,438,952	8/8/95	Otsuka	117	84	1/31/94
	A61	5,439,876	8/8/95	Graf et al.	505	447	8/16/93
•	A62	5,441,703	8/15/95	Jurgensen	422	129	3/29/94
·	A63	5,443,033	8/22/95	Nishizawa et al.	117	86	3/11/94
	A64	5,443,647	8/22/95	Aucoin et al.	118	723 ME	7/11/94
	A65	5,455,072	10/3/95	Bension et al.	427	255.7	11/18/92
	A66	5,458,084	10/17/95	Thorne et al.	117	89	12/9/93
	A67	5,469,806	11/28/95	Mochizuki et al.	117	97	8/20/93
	A68	5,480,818	1/2/96	Matsumoto et al.	437	40	2/9/93
	A69	5,483,919	1/16/96	Yokoyama et al.	117	89	8/17/94
	A70	5,484,664	1/16/96	Kitahara et al.	428	641	1/21/94
	A71	5,503,875	4/2/96	Imai et al.	427	255.3	3/17/94
	A72	5,521,126	5/28/96	Okamura et al.	437	235	6/22/94
- <u></u>	A73	5,527,733	6/18/96	Nishizawa et al.	437	160	2/18/94
	A74	5,532,511	7/2/96	Nishizawa et al.	257	627	3/23/95
	A75	5,540,783	7/30/96	Eres et al.	118	725	5/26/94
	A76	5,580,380	12/3/96	Liu, et al.	117	86	1/30/95
	A77	5,601,651	2/11/97	Watabe	118	715	12/14/94
	A78	5,609,689	3/11/97	Kato et al.	118	719	6/3/96
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•	A79	5,616,181	4/1/97	Yamamoto et al.	118	723 ER	11/21/95
	A80	5,637,530	6/10/97	Gaines et al.	114	105	6/10/96
	A81	5,641,984	6/24/97	Aftergut et al.	257	433	8/19/94
	A82	5,644,128	7/1/97	Wollnik et al.	250	251	8/25/94
	A83	5,667,592	9/16/97	Boitnott et al.	118	719	4/16/96
	A84	5,674,786	10/7/97	Turner et al.	437	225	6/5/95
	A85	5,693,139	12/2/97	Nishizawa et al.	117	89	6/15/93
	A86	5,695,564	12/9/97	Imahashi	118	719	8/3/95
	A87	5,705,224	1/6/98	Murota et al.	427	248.1	1/31/95
	A88	5,707,880	1/13/98	Aftergut et al.	437	3	1/17/97
	A89	5,711,811	1/27/98	Suntola et al.	118	711	11/28/95
	A90	5,730,801	3/24/98	Tepman et al.	118	719	8/23/94
	A91	5,730,802	3/24/98	Ishizumi et al.	118	719	12/27/96
	A92	5,747,113	5/5/98	Tsai	427	255.5	7/29/96
	A93	5,749,974	5/12/98	Habuka et al.	118	725	7/13/95
	A94	5,788,447	8/4/98	Yonemitsu et al.	414	217	8/5/96
	A95	5,788,799	8/4/98	Steger, et al.	156	345	6/11/96
	A96	5,796,116	8/18/98	Nakata et al.	257	66	7/25/95
	A97	5,801,634	9/1/98	Young et al.	340	635	9/8/97
	A98	5,807,792	9/15/98	Ilg et al.	438	758	12/18/96
	A99	5,830,270	11/3/98	McKee et al.	117	106	8/5/96
	A100	5,835,677	11/10/98	Li et al.	392	401	10/3/96
	A101	5,851,849	12/22/98	Comizzoli et al.	438	38	5/22/97
	A102	5,855,675	1/5/99	Doering et al.	118	719	3/3/97
	A103	5,855,680	1/5/99	Soininen et al.	118	719	11/28/95
	A104	5,856,219	1/5/99	Naito et al.	438	241	8/18/97
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	A105	5,858,102	1/12/99	Tsai	118	719	2/14/98
•	A106	5,866,213	2/2/99	Foster et al.	427	573	7/19/97
	A107	5,866,795	2/2/99	Wang et al.	73	1.36	3/17/97
	A108	5,879,459	3/9/99	Gadgil et al.	118	715	8/29/97
	A109	5,882,165	3/16/99	Maydan et al.	414	217	9/10/97
	A110	5,882,413	3/16/99	Beaulieu et al.	118	719	7/11/97
	A111	5,904,565	5/18/99	Nguyen, et al.	438	687	7/17/97
	A112	5,916,365	6/29/99	Sherman	117	92	8/16/96
	A113	5,923,056	7/13/99	Lee et al.	257	192	3/12/98
	A114	5,923,985	7/13/99	Aoki et al.	438	301	1/14/97
	A115	5,925,574	7/20/99	Aoki et al.	437	31	4/10/92
	A116	5,928,389	7/27/99	Jevtic	29	25.01	10/21/96
	A117	5,942,040	8/24/99	Kim et al.	118	726	8/27/97
	A118	5,947,710	9/7/99	Cooper, et al.	418	63	6/16/97
	A119	5,972,430	10/26/99	DiMeo, Jr. et al.	427	255.32	11/26/97
	A120	6,001,669	12/14/99	Gaines et al.	438	102	7/21/92
	A121	6,015,590	1/18/00	Suntola et al.	427	255.23	11/28/95
	A122	6,025,627	2/15/00	Forbes et al.	257	321	5/29/98
	A123	6,036,773	3/14/00	Wang et al.	117	97	3/27/97
	A124	6,042,652	3/28/00	Hyun et al.	118	719	9/7/99
	A125	6,043,177	3/28/00	Falconer et al.	502	4	1/21/97
	A126	6,051,286	4/18/00	Zhao et al.	427	576	8/22/97
	A127	6,062,798	5/16/00	Muka	414	416	6/13/96
	A128	6,071,808	6/6/00	Merchant et al.	438	633	6/23/99
	A129	6,084,302	7/4/00	Sandhu	257	751	12/26/95
	A130	6,086,677	7/11/00	Umotoy et al.	118	715	6/16/98
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	A131	6,110,556	8/29/00	Bang, et al.	428	64.1	10/17/97
	A132	6,113,977	9/5/00	Soininen et al.	427	64	9/11/97
	A133	6,117,244	9/12/00	Bang, et al.	118	715	3/24/98
	A134	6,124,158	9/26/00	Dautartas et al.	438	216	6/8/99
	A135	6,130,147	10/10/00	Major et al.	438	604	3/18/97
	A136	6,139,700	10/31/00	Kang et al.	204	192.17	9/30/98
	A137	6,140,237	10/31/00	Chan et al.	438	687	4/19/99
	A138	6,140,238	10/31/00	Kitch	438	687	4/21/99
	A139	6,143,659	11/7/00	Leem	438	688	8/27/98
	A140	6,144,060	11/7/00	Park et al.	257	310	7/31/98
	A141	6,158,446	12/12/00	Mohindra et al.	134	25.4	9/4/98
	A142	6,174,377	1/16/01	Doering, et al.	118	729	1/4/99
	A143	6,174,809	1/16/01	Kang, et al.	438	682	12/15/98
	A144	6,200,893	3/13/01	Sneh	438	685	3/11/98
	A145	6,203,613	3/20/01	Gates, et al.	117	104	10/19/99
-	A146	6,206,967	3/27/01	Mak, et al.	118	666	6/14/00
	A147	6,207,302	3/27/01	Sugiura, et al.	428	690	3/2/98
	A148	6,248,605	6/19/01	Harkonen, et al.	438	29	6/2/99
	A149	6,270,572	8/7/01	Kim, et al.	117	93	8/9/99
	A150	6,271,148	8/7/01	Kao et al.	438	727	10/13/99
	A151	6,287,965	9/11/01	Kang, et al.	438	648	2/23/00
	A152	6,291,876	9/18/01	Stumborg, et al.	257	632	8/20/98
	A153	6,305,314	10/23/01	Sneh, et al.	118	723 R	12/17/99
	A154	6,306,216	10/23/01	Kim, et al.	118	725	7/12/00
	A155	6,316,098	11/13/01	Yitzchaik, et al.	428	339	3/23/99
	A156	2001/0042799	11/22/01	Kim, et al.	239	553	2/2/01
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	A157	2001/0041250	11/15/01	Werkhoven et al	. 428	212	3/6/01
	A158	2001/0034123	10/25/01	Jeon, et al.	438	643	4/6/01
	A159	2001/0031562	10/18/01	Raaijmakers et al.	438	770	2/22/01
	A160	2001/0011526	8/9/01	Doering, et al.	118	729	1/16/01
	A161	2001/0009140	7/26/01	Bondestam, et al.	118	725	1/25/01
	A162	2001/0000866	5/10/01	Sneh, et al.	118	723 R	11/29/00
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.



(PTO Form		of Commerce, Pate	TR and Trademark		Docket No RF APPM/64	EIVED	Serial No.	ρ
		LIST OF PATENT	S AND PUBLICA	TIONS	Applicable		Confirmation	
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Foreign Pa	atent D	ocuments	own BADE	MARI				_
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translat YES	tion
	B1	196 27 017A1	1/9/97	DE	H01L	21/283		
•	B2	198 20 147A1	7/1/99	DE	H01L	21/3205		
	В3	0 429 270 A2	5/29/91	EP	G03F	Jul-36		
	B4	0 799 641 A2	10/8/97	EP	B01J	20/32		一
	B5	0 442 290 A1	2/14/91	EP	C30B	25/02		
	В6	0 344 352 A1	6/3/88	EP	H01L	39/24		10
	В7	2.626.110	7/21/89	FR	H01L	39/24		
	B8	2.692.597	12/24/93	FR	C23C	16/00	\boxtimes	
	В9	2 355 727A	05/02/12001	GB	C23C	16/44	\boxtimes	
	B10	58-098917	6/13/83	JP	H01L	21/205	\boxtimes	
	B11	58-100419	6/15/83	JP	H01L	21/20	\boxtimes	
	B12	60-065712A	4/15/85	JP	C01B	33/113		
	B13	61-035847	2/20/86	JP	B01J	19/08	\boxtimes	
	B14	61-210623	9/18/86	JP	H01L	21/205	\boxtimes	
	B15	62-069508	3/30/87	JP	H01L	21/203	\boxtimes	
	B16	62-091,495	4/25/87	JP	C30B	25/02	\boxtimes	
	B17	62-141717	6/25/87	JP	H01L	21/203	\boxtimes	
	B18	62-167297	7/23/87	JP	C30B	29/40	\boxtimes	
	B19	62-171999	7/28/87	JP	C30B	29/40	\boxtimes	
	B20	62-232919	10/13/87	JP	H01L	21/205	\boxtimes	
	B21	63-062313	3/18/88	JP	H01L	21/203	\boxtimes	
	B22	63-085098	4/15/88	JP	C30B	21/40	\boxtimes	
	B23	63-090833	4/21/88	JP	H01L	21/365	\boxtimes	
	B 24	63-222420	9/16/88	JP	H01L	21/205	\boxtimes	
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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.



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(PTO Form			UTO AND DUDI	10ATIONS	APPM/64	o.RECEIVI	+40/074,89	8
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				105	Yoon, et a	HOLUGY CENT	EUnkorown	
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Foreign Pa	atent D	ocuments	VB.	MOEMARY				
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	B25	63-222421	9/16/88	JP	H01L	21/205		110
	B26	63-227007	9/21/88	JP	H01L	21/205		十六
	B27	63-252420	10/19/88	JP	H01L	21/205		十六
	B28	63-266814	11/2/88	JP	H01L	21/205		十一
	B29	64-009895	1/13/89	JP	C30B	29/40		+
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	B31	64-009897	1/13/89	JP	C30B	29/40	\boxtimes	十一
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	B33	64-082615	3/28/89	JP	H01L	21/205		一
	B34	64-082617	3/28/89	JP	H01L	21/205	\boxtimes	+
	B35	64-082671	3/28/89	JP	H01L	29/78		
	B36	64-082676	3/28/89	JP	H01L	29/80	\boxtimes	
	B37	64-090524	4/7/89	JP	H01L	21/205	\boxtimes	
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	B39	01-103996	4/21/89	JP	C30B	29/40	\boxtimes	
	B40	01-117017	5/9/89	JP	H01L	21/203	\boxtimes	
	B41	01-143221	6/5/89	JP	H01L	21/314	\boxtimes	
	B42	01-143233	6/5/89	JP	H01L	21/76	\boxtimes	
	B43	01-154511	6/16/89	JP	H01L	21/20	\boxtimes	
	B44	01-236657	9/21/89	JP	H01L	29/80		
	B45	01-245512	9/29/89	JP	H01L	21/205	\boxtimes	
	B46	01-264218	10/20/89	JP	H01L	21/205	\boxtimes	
	B47	01-270593	10/27/89	JP	C30B	25/02	\boxtimes	
	B48	01-272108	10/31/89	JP	H01L	21/203	\boxtimes	

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		of Commerce, Pate			Docket No.	RECEI	Serial No. 10/074,898	^
(PTO Form		nodified) LIST OF PATEN	ITE AND DURL	PIONT	APPM/647		1	
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				S. Gill	Yoon, etal	HNOLOGY CE	- rinksean	
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Initial		Number					YES	NO
	B49	01-290221	11/22/89	JP	H01L	21/205	\boxtimes	
	B50	01-290222	11/22/89	JP	H01L	21/205		
	B51	01-296673	11/30/89	JP	H01L	29/88	\boxtimes	
	B52	01-303770	12/7/89	JP	H01L	39/24	\boxtimes	
	B53	01-305894	12/11/89	JP	C30B	23/08	\boxtimes	
	B54	01-313927	12/19/89	JP	H01L	21/205	\boxtimes	
-	B55	02-012814	1/17/90	JP	H01L	21/205		
	B56	02-014513	1/18/90	JP	H01L	21/205		
	B57	02-017634	1/22/90	JP	H01L	21/225		
	B58	02-063115	3/2/90	JP	H01L	21/20	\boxtimes	
	B59	02-074029	3/14/90	JP	H01L	21/205		
	B60	02-074587	3/14/90	JP	C30B	23/08		
	B61	02-106822	4/18/90	JP	H01B	13/00		
	B62	02-129913	5/18/90	JP	H01L	21/205		
	B63	02-162717	6/22/90	JP	H01L	21/20		
	B64	02-172895	7/4/90	JP	C30B	29/36		
	B65	02-196092	8/2/90	JP	C30B	25/14		
	B66	02-203517	8/13/90	JP	H01L	21/205		
	B67	02-230690	9/13/90	JP	H05B	33/10		
	B68	02-230722	9/13/90	JP	H01L	21/205		
	B69	02-246161	10/1/90	JP	H01L	29/784		
	B70	02-264491	10/29/90	JP	H01S	18-Mar		1
	B71	02-283084	11/20/90	JP	H01S	18-Mar		
	B72	02-304916	12/18/90	JP	H01L	21/205		+=
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U.S. Depar	rtment c	of Commerce, Pat	ent and Tradem	ark Office	Docket No.	REU	Serial No.	
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Foreign Pa	atent D	ocuments	Ext.	AMERICA COUNTRY				
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	B73	03-019211	1/28/91	JP	H01L	21/205	N	NO
	B74	03-022569	1/30/91	JP	H01L	29/804		
	B75	03-023294	1/31/91	JP	C30B	25/18		
	B76	03-023299	1/31/91	JP	C30B	29/40		
	B77	03-044967	2/26/91	JP	H01L	29/48		片
	B78	03-048421	3/1/91	JP	H01L	21/302		片片
	B79	03-070124	3/26/91	JP	H01L	21/205		片片
	B80	03-185716	8/13/91	JP	H01L	21/205		片
	B81	03-208885	9/12/91	JP	C30B	23/02	\boxtimes	一
	B82	03-234025	10/18/91	JP	H01L	21/318		一
	B83	03-286522	12/17/91	JP	H01L	21/205		
	B84	03-286531	12/17/91	JP	H01L	21/316		
	B85	04-031391	2/3/92	JP	C30B	23/08	\boxtimes	
	B86	04-031396	2/3/92	JP	C30B	25/14		
	B87	04-031396	2/3/92	JP	C30B	25/14	\boxtimes	
	B88	04-100292	4/2/92	JP	H01S	18-Mar	\boxtimes	
	B89	04-111418	4/13/92	JP	H01L	21/205	\boxtimes	
	B90	04-132214	5/6/92	JP	H01L	21/205		
	B91	04-132681	5/6/92	JP	C30B	25/14	\boxtimes	
	B92	04/151822	5/25/92	JP	H01L	21/205	\boxtimes	
	B93	04-162418	6/5/92	JP	H01L	21/205	\boxtimes	
	B94	04-175299	6/23/92	JP	C30B	29/68		
	B95	04-186824	7/3/92	JP	H01L	21/205	\boxtimes	
	B96	04-212411	8/4/92	JP	H01L	21/203		
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	B97	04-260696	9/16/92	JP	C30B	29/40		
	B98	04-273120	9/29/92	JP	H01L	21/20		
	B99	04-285167	10/9/92	JP	C23C	14/54		
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	B100	04-325500	11/13/92	JP	C30B	33/00		
	B101	04-328874	11/17/92	JP	H01L	29/804		
	B102	05-029228	2/5/93	JP	H01L	21/205		
	B103	05-047665	2/26/93	JP	H01L	21/205		╁┼
	B105	05-047666	2/26/93	JP	H01L	21/205		
	B106	05-047668	2/26/93	JP	H01L	21/205		╁∺
	B107	05-074717	3/26/93	JP	H01L	21/205		╁╫
	B108	05-074724	3/26/93	JP	H01L	21/205		╁
	B109	05-102189	4/23/93	JP	H01L	21/336		╁
	B110	05-160152	6/25/93	JP	H01L	21/336		
	B111	05-175143	7/13/93	JP	H01L	21/205		片片
	B112	05-175145	7/13/93	JP	H01L	21/205		片片
	B113	05-182906	7/23/93	JP	H01L	21/20		十一
 	B114	05-186295	7/27/93	JP	C30B	25/02		
	B115	05-206036	8/13/93	JP	H01L	21/205	\boxtimes	十一
	B116	05-234899	9/10/93	JP	H01L	21/205		计员
	B117	05-235047	9/10/93	JP	H01L	21/338		
	B118	05-251339	9/28/93	JP	H01L	21/20	\boxtimes	十一
	B119	05-270997	10/19/93	JP	C30B	29/68	\boxtimes	1 1
	B120	05-283336	10/29/93	JP	H01L	21/20	\boxtimes	
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U.S. Department of Commerce, Patent and Trademark Office					Docket No	Docket No.		Serial No.	
(PTO Form	1449 mc	odified)	APPM/647	APPM/6473		RF0/074,898			
		IST OF PATENT	Applicant	Applicant		Confirmation No.:			
CITED BY	APPLICA	AN I	61	PEVO	Yoon, et al	. TECHNOL	UN 14 200 Unknown UGY CENTER Group	?	
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Foreign Pa	atent Doo	cuments	W.	D. OFMARK			· · ·	·	
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	B121	05-291152	11/5/93	JP	H01L	21/205			
	B122	05-304334	11/16/93	JP	H01L	18-Mar			
	B123	05-343327	12/24/93	JP	H01L	21/205	\boxtimes		
	B124	05-343685	12/24/93	JP	H01L	29/784	\boxtimes		
	B125	06-045606	2/18/94	JP	H01L	29/784	\boxtimes		
	B126	06-132236	5/13/94	JP	H01L	21/205			
	B127	06-177381	6/24/94	JP	H01L	29/784			
	B128	06-196809	7/15/94	JP	H01S	18-Mar			
	B129	06-222388	8/12/94	JP	G02F	1/136	\boxtimes		
	B130	06-224138	8/12/94	JP	H01L	21/205	\boxtimes		
	B131	06-230421	8/19/94	JP	G02F	1/136	\boxtimes		
	B132	06-252057	9/9/94	JP	H01L	21/205	\boxtimes		
	B133	06-291048	10/18/94	JP	H01L	21/205			
	B134	07-086269	3/13/95	JP	H01L	21/314	\boxtimes		
	B135	07-070752	3/14/95	JP ·	C23C	16/40	\boxtimes		
	B136	08-181076	7/12/96	JP	H01L	21/205	\boxtimes		
	B137	08-245291	9/24/96	JP	C30B	25/14		市	
	B138	08-264530	10/11/96	JP	H01L	21/3205			
	B139	09-260786	10/3/97	JP	H01S	18-Mar	\boxtimes	一	
	B140	09-293681	11/11/97	JP	H01L	21/205	\boxtimes	I	
	B141	10-188840	7/21/98	JP	H01J	29/18		一	
	B142	10-190128	7/21/98	JP	H01S	18-Mar	\boxtimes	一一	
	B143	10-308283	11/17/98	JP	H05B	33/22	\boxtimes		
	B144	11-269652	10/5/99	JP	C23C	16/44	\boxtimes	片片	
	B145	11-269652	10/5/99	JP	C23C	16/44	\boxtimes		
	B146	2000-031387	1/28/00	JP	H01L	27/04	\boxtimes		
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U.S. Department of Commerce, Patent and Trademark Office					Docket No.		Serial No.		
(PTO Form 1449 modified)						APPM/6473 RF		19/074,898	
SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT						Applicant		n No.:	
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Initial		Number					YES	NO	
	B147	2000-058777	2/25/00	JP	H01L	27/108			
	B148	2000-068072	3/3/00	JP	H05B	33/22	\boxtimes		
	B149	2000-087029	3/28/00	JP	C09K	8-Nov	\boxtimes		
	B150	2000-319772	3/28/00	JP	C23C	16/00	\boxtimes		
	B151	2000-138094	5/16/00	JP	H05B	33/10	\boxtimes		
	B152	2000-218445	8/8/00	JP	B23P	Jun-00	\boxtimes		
	B153	2000-319772	11/21/00	JP	C23C	14/24	\boxtimes		
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	B156	2001-020075	1/23/01	JP	C23C	16/44			
	B157	2001-62244	3/13/01	JP	B01D	53/34			
	B158	2001-152339	6/5/01	JP	C23C	16/40	\boxtimes		
	B159	2001-172767	6/26/01	JP	C23C	16/40			
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	B163	2001-220294	8/14/01	JP	C30B	29/20	\boxtimes		
	B164	2001-240972	9/4/01	JP	C23C	16/458		\boxtimes	
	B165	2001-254181	9/18/01	JP	C23C	16/46			
	B166	2001-284042	10/12/01	JP	H05B	33/04			
	B167	2001-303251	10/31/01	JP	C23C	16/44			
	B168	2001-328900	11/27/01	JP	C30B	29/68			
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	B171	93/0211	2/4/93	WO	C08F	Apr-78			
	B172	96/17107	6/6/96	WO	C23C	16/44			
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SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS						APPM/6473 Applicant		n No.:
CITED BY	APPLICA	AN I	6	PE	Yood Det a	2002	Unknown	
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Initial							YES	NO
	B173	96/18756	6/20/96	WO	C23C	16/08		
	B174	98/06889	2/19/98	WO	D06F			
	B175	98/51838	11/19/98	WO	C23C	16/06		
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	B177	99/29924	6/17/99	WO	C23C	16/04		
	B178	99/41423	8/19/99	WO	C23C			
-	B179	00/11721	3/2/00	WO	H01L	29/43		
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(PTO Form 1449 modified) SUPPLEMENTAL LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT					APPM/6473	10/074,898	
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